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**Reliability Data Summary:**

QV DEVICE NAME: NCV7517BFTR2G

PACKAGE: LQFP 32

Test	Specification	Condition	Interval	Results
HTOL	JESD22-A108	Ta=125°C, 100 % max rated Vcc	1008 hrs	0/240
HTSL	JESD22-A103	Ta=150°C	1008 hrs	0/80
TC	JESD22-A104	Ta= -65°C to +150°C	500 cyc	0/240
HAST	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs	0/239
uHAST	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs	0/240
PC	J-STD-020 JESD-A113	MSL 2 @ 260 °C		0/720
SD	JSTD002	Ta = 245C, 10 sec		0/ 45

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Electrical Characteristic Summary:

Device parameters will continue to meet all Datasheet specifications and reliability will meet or exceed ON Semiconductor established standards.

List of Affected Standard Parts:

Part Number	Qualification Vehicle
NCV7513BFTR2G	NCV7517BFTR2G
NCV7517BFTR2G	NCV7517BFTR2G